

<b>Search Notes</b>  	<b>Application/Control No.</b>  10561014	<b>Applicant(s)/Patent Under Reexamination</b>  PAN ET AL.
	<b>Examiner</b>  Chang-Yu Wang	<b>Art Unit</b>  1649

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Sequence search: SEQ ID NOs:1, 3 and 36 regular and oligomer search. See search results in SCORE (6/18/08).	4/9/09	CYW
EAST, STN: search strategy attached (updated).	4/9/09	CYW
Inventor name search: EAST, STN, PALM (updated).	4/9/09	CYW
PLUS search from STIC. See search results in eDAN (2/17/09).	4/9/09	CYW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/C.Y. W./  
Examiner.Art Unit 1649